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CORRECTION

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Correction: An innovative *in situ* AFM system for a soft X-ray spectromicroscopy synchrotron beamline

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Correction for 'An innovative *in situ* AFM system for a soft X-ray spectromicroscopy synchrotron beamline' by Aljoša Hafner *et al.*, *Analyst*, 2024, **149**, 700–706, https://doi.org/10.1039/D3AN01358H.

In the published article, the authors incorrectly presented the in-vacuum resonance curve shown in Fig. 3c.

An instrumental acquisition error resulted in the AFM cantilever's oscillation amplitude being incorrectly linked to the excitation frequency. Consequently, the frequency sweep in the original article exhibits a significantly different *Q*-factor. While the incorrect **IN-VACUUM** sweep and the associated *Q*-factor have no effect on the raw AFM images, the subsequent data analysis, or the conclusions presented in the article, these values may lead to incorrect calculations of the *Q*-factor changes from air to vacuum. Therefore, the corrected frequency sweeps are shown in the new version of Fig. 3 below.

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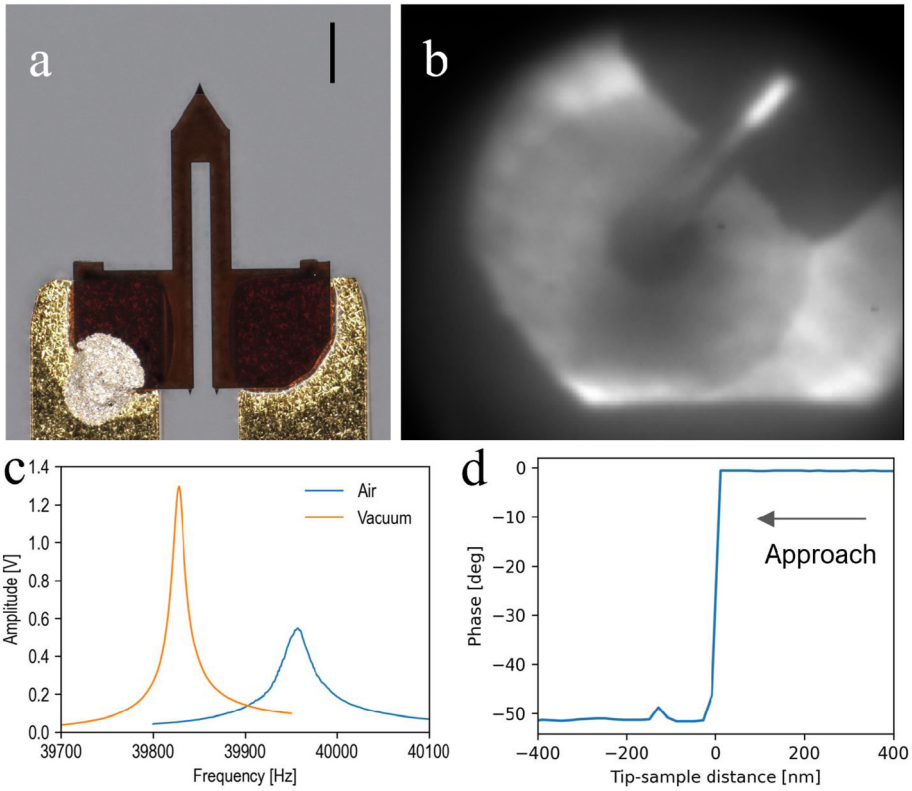

Fig. 3 AFM tuning fork and cantilever. Visible light image (a) with 100 μm scale bar. X-ray TX projection (b) showing the tip in front of the zone plate optics and the central stop. Normalized resonance sweep in air (blue) and under vacuum (orange) (c), showing the expected increase of the *Q* factor under vacuum. Tip–sample approach curve (d) showing a sudden decrease of the phase at the tip–sample mechanical contact point, indicating a rapid shift of the resonance.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.